

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10049647	TOILLON ET AL.
	Examiner	Art Unit
	Rutkowski, Jeffrey	2619

SEARCHED

Class	Subclass	Date	Examiner
370	351, 389, 392, 401 (updated search)	08/22/2008	JMR
370	242 (physical layer and logical layer analysis concepts)s	08/22/2008	JMR

SEARCH NOTES

Search Notes	Date	Examiner
searched EAST for logical and physical layer analysis concepts	08/22/2008	JMR

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
370	242, 389, 401 (see attached notes)	08/22/2008	JMR

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